

# III/V-on-Si based Single-Chip Beam Scanner LiDAR

---

**Kyoungho Ha**, Dongjae Shin, Hyunil Byun, Kyunghyun Son, Changgyun Shin, Woosung Kim, Eun Kyung Lee, Dongsik Shim, Bongyong Jang, Inoh Hwang, Tatsuhiro Otsuka, Changbum Lee, Jisan Lee, Hankyu Lee, and Hyuck Choo

*Advance Sensor Lab, Samsung Advanced Institute of Technology, Samsung Electronics*

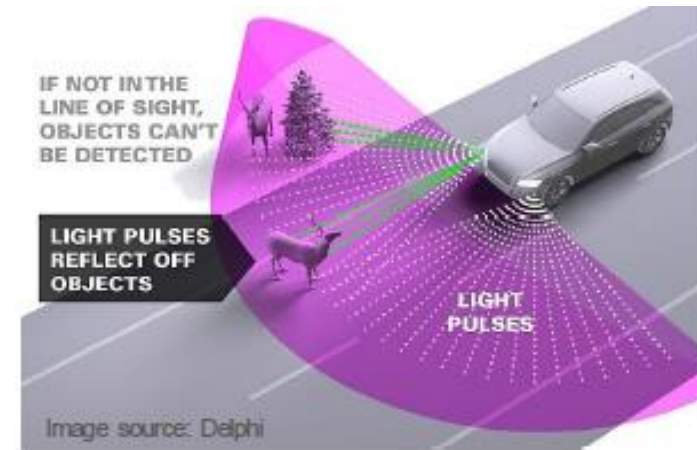
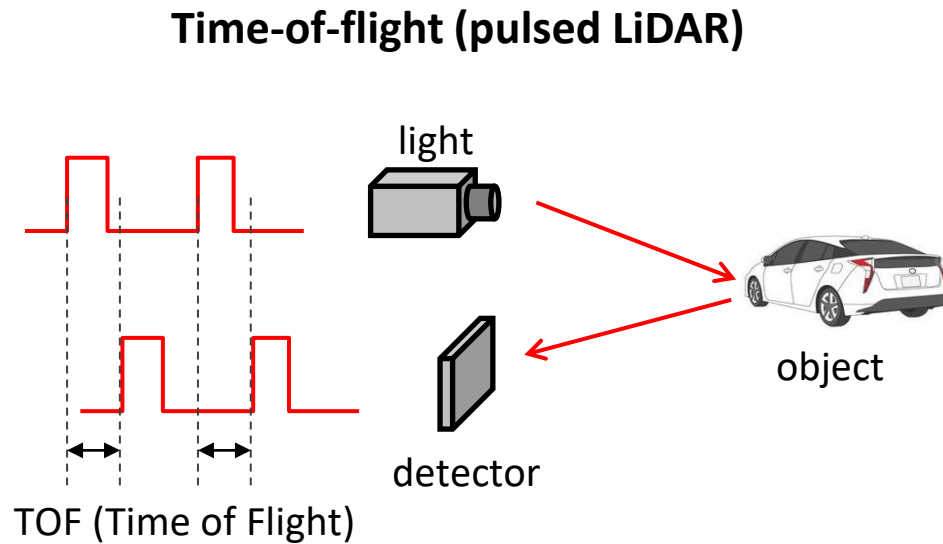
Disclaimer : The views expressed herein are those of the presenter; they do not necessarily reflect the views of Samsung Advanced Institute of Technology, or Samsung Electronics.

# Outline

- Introduction
- LiDAR Technologies
  - Wavelength, Illumination, Scanning and Detection
  - Our approach : Light Source Integrated Photonic IC
- Results
  - Chip, Beam Scanning, Module, Ranging, Demonstration and Field Test
- Summary

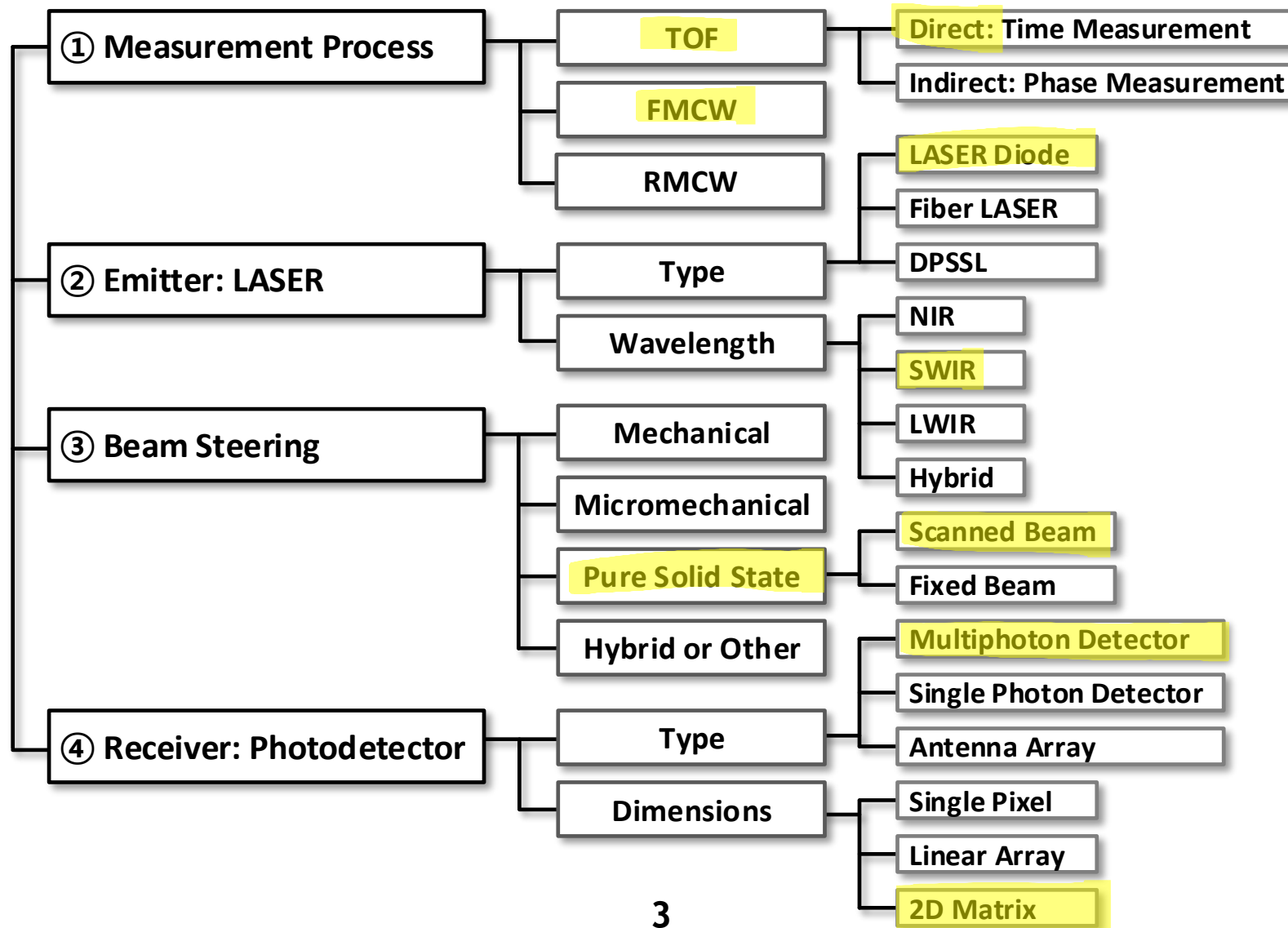
# Introduction : LiDAR

- LiDAR: Light Detection and Ranging
- Distance measurement by Time of Flight (TOF)
- Applications: Autonomous Driving, Robot, Mobile, Security, etc.



**(Object Detection)**

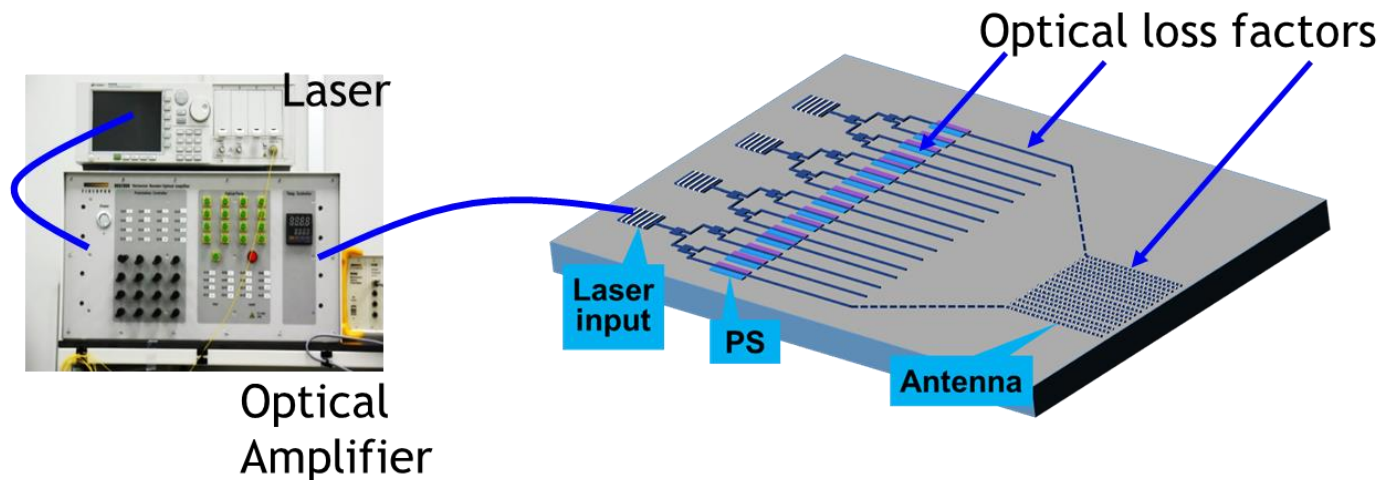
# Our Approach



# Light Source integrated Photonic IC

- Problems of existing OPA LiDAR
  - ① External wavelength-tunable laser source required

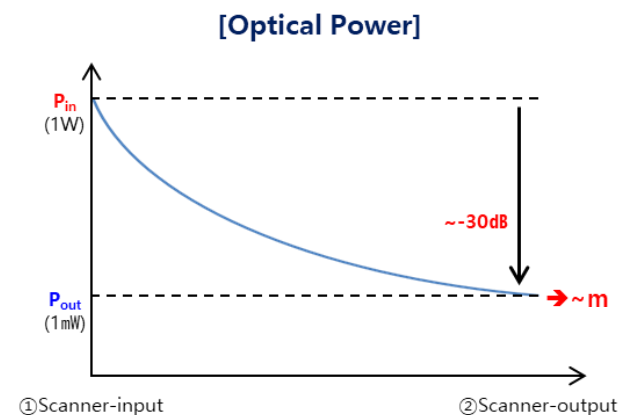
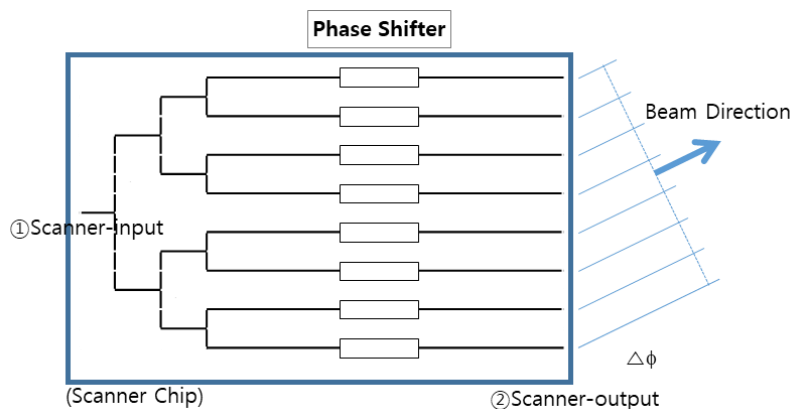
→ Solution : Light source integrated Photonic IC



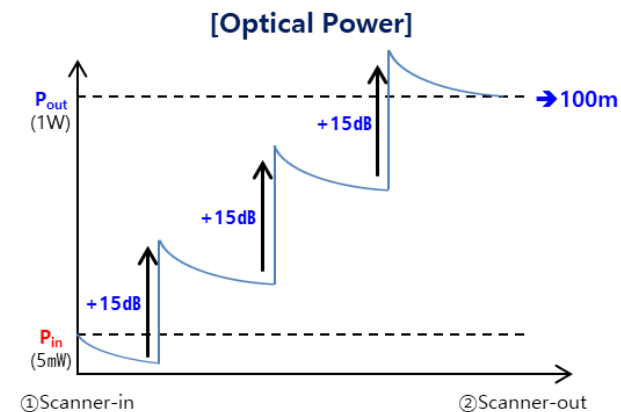
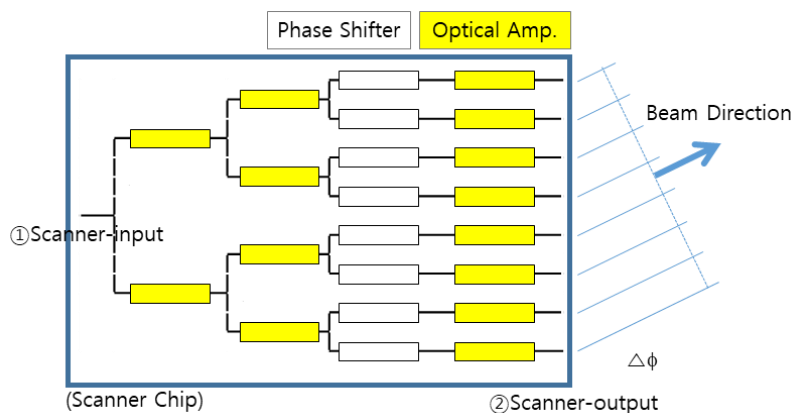
# Light Source integrated Photonic IC

② High loss (10~30dB) through phase shifter, waveguide, grating antenna, ...

➔ Solution : Distributed Optical Amplification



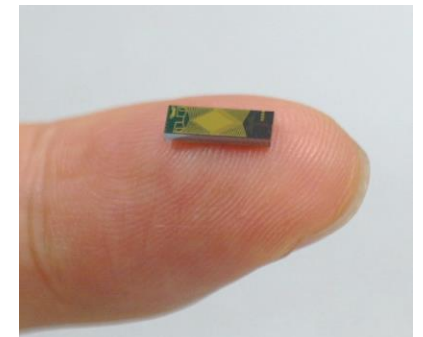
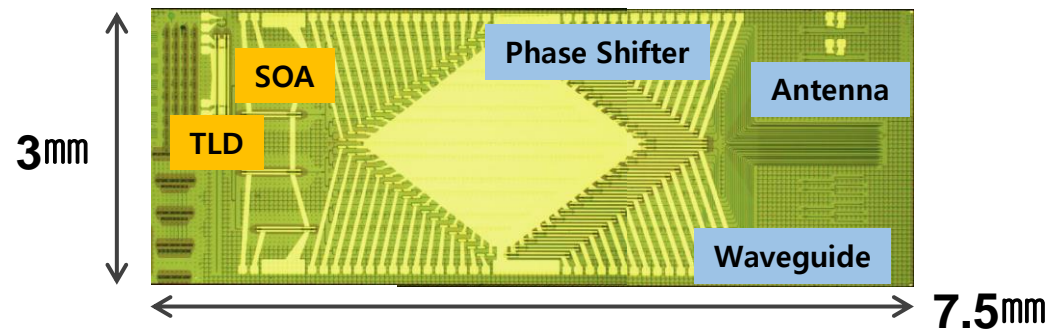
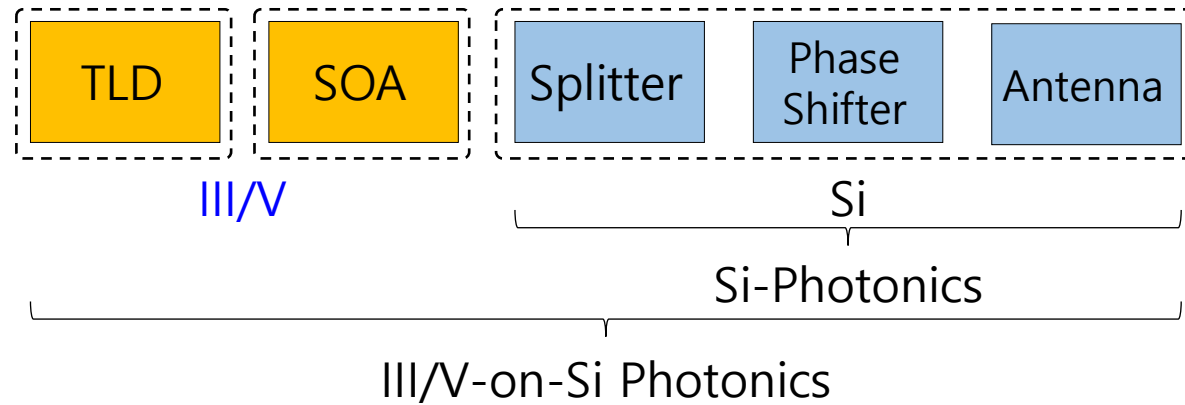
(w/o SOA)



(w/ SOA)

# Our Results : Chip

- All photonic functions integrated on 7.5 x 3mm<sup>2</sup> single chip
  - III/V-on-Si Photonic process used for TLD, SOA and Si-Photonic IC

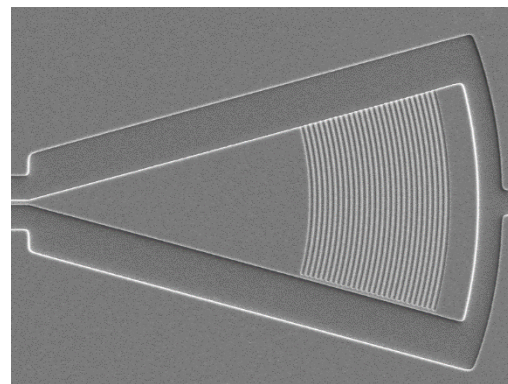
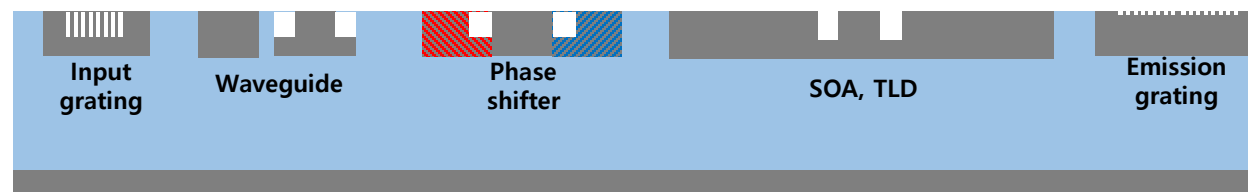


# Our Results : Fabrication process

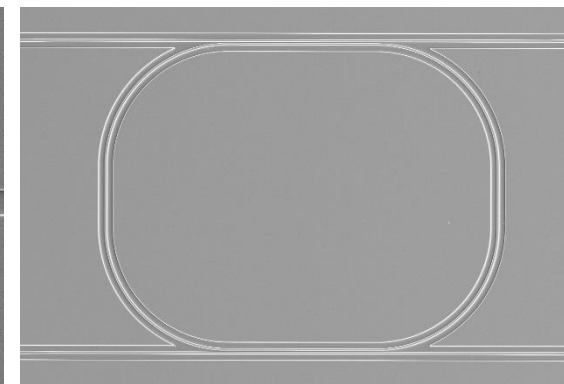
- Ggrating, waveguide, phase shifter, and emission grating defined
- Triple-depth etch (full, ~half, shallow)

Si Fab

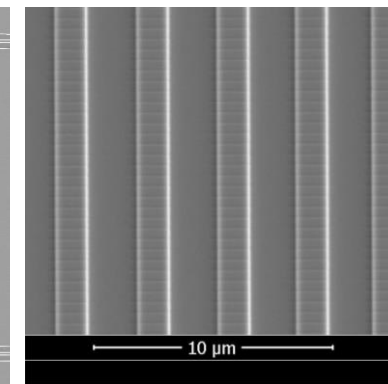
8" SOI wafer



Input grating



Waveguide (Ring)

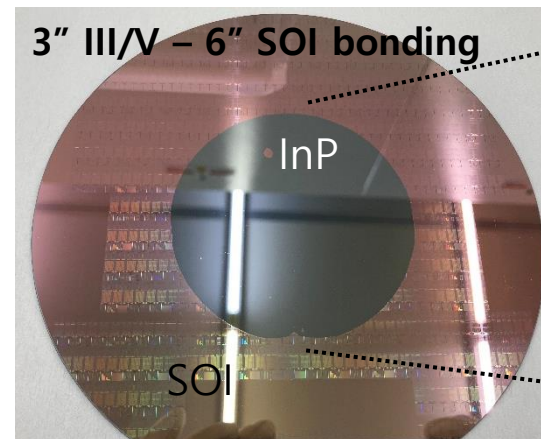
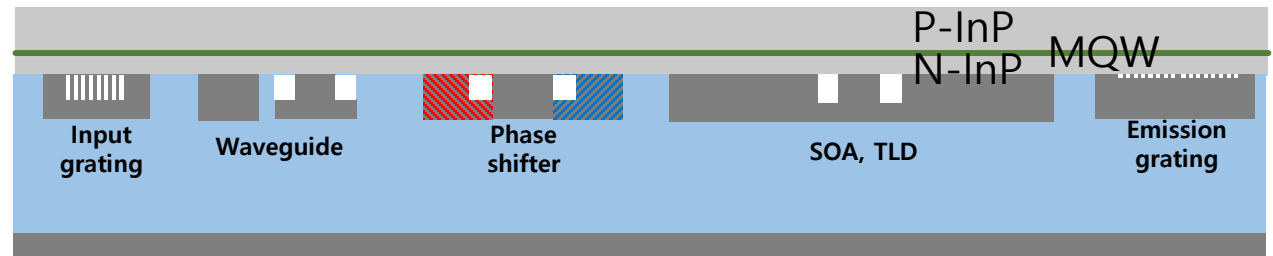
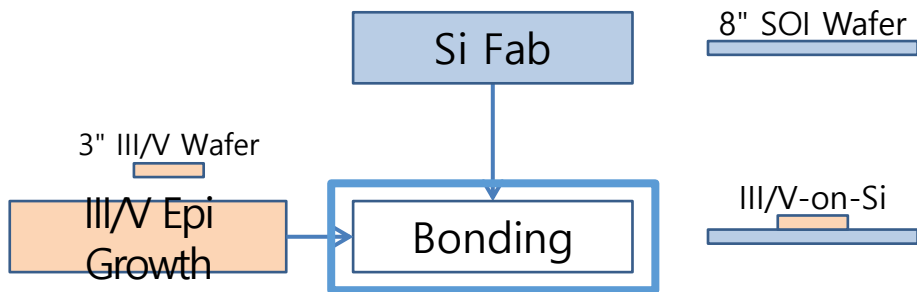


Emission grating

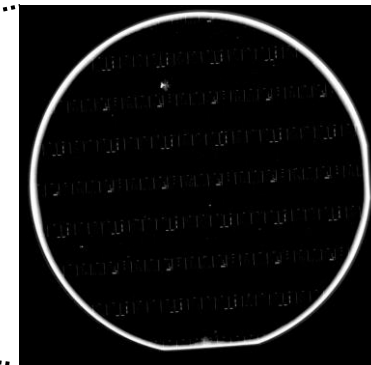


# Our Results : Fabrication process

- Direct bonding between III/V Epi wafer and patterned Si wafer
- Cleaning → O<sub>2</sub> plasma activation → bonding
- Selective wet etching for InP sub. removal

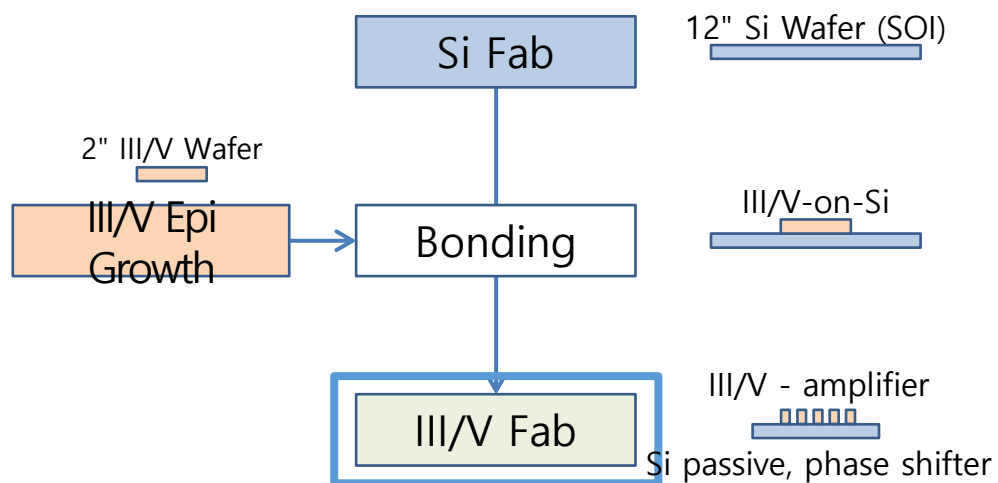


8 Light camera

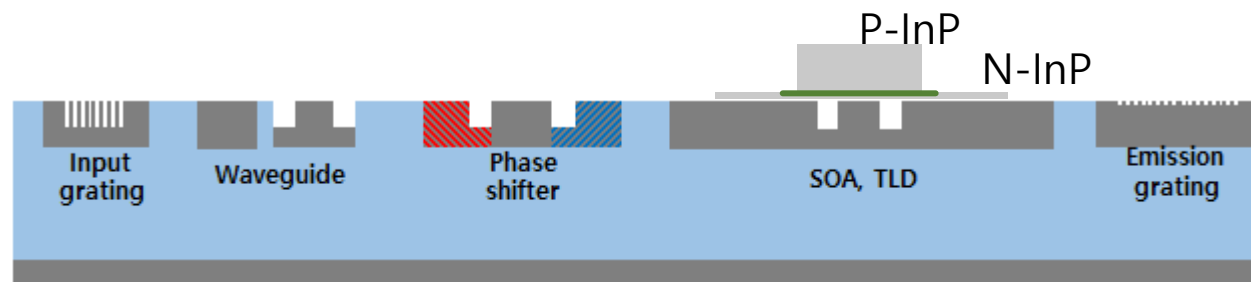


SAM  
 (Scanning Acoustic  
 Microscope)

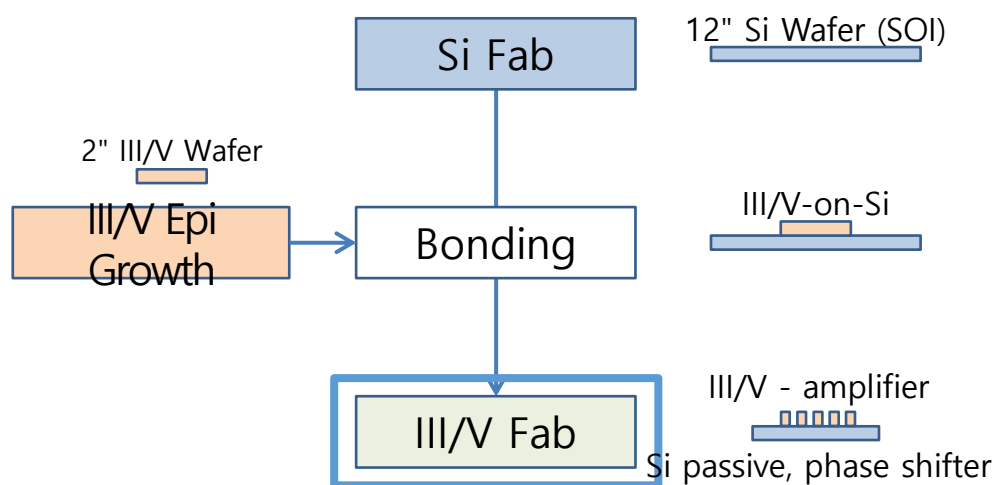
# Our Results : Fabrication process



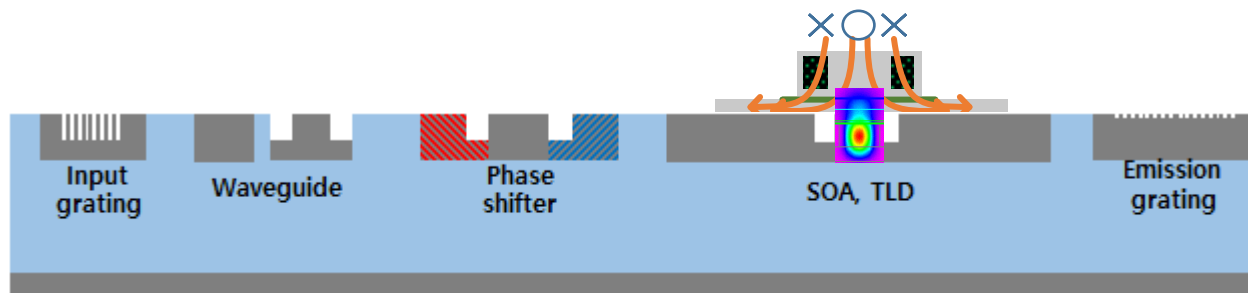
- Mesa structure defined



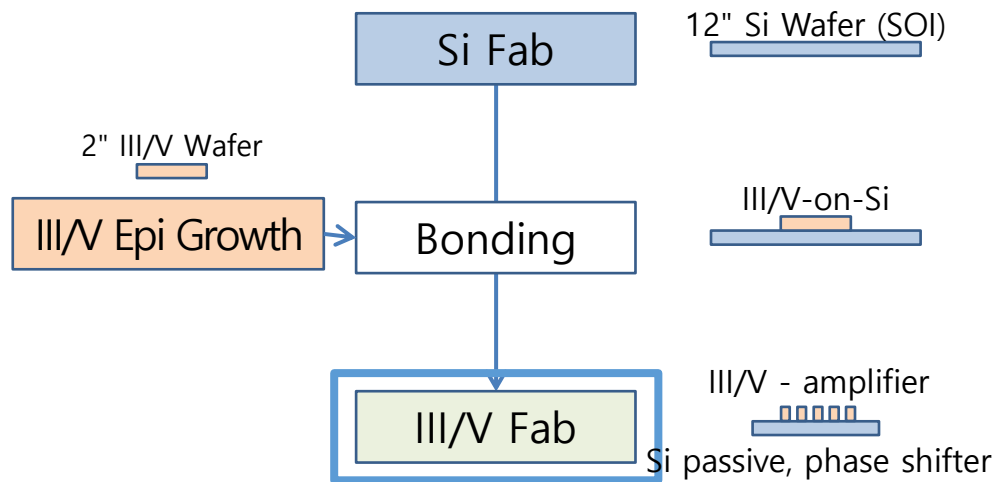
# Our Results : Fabrication process



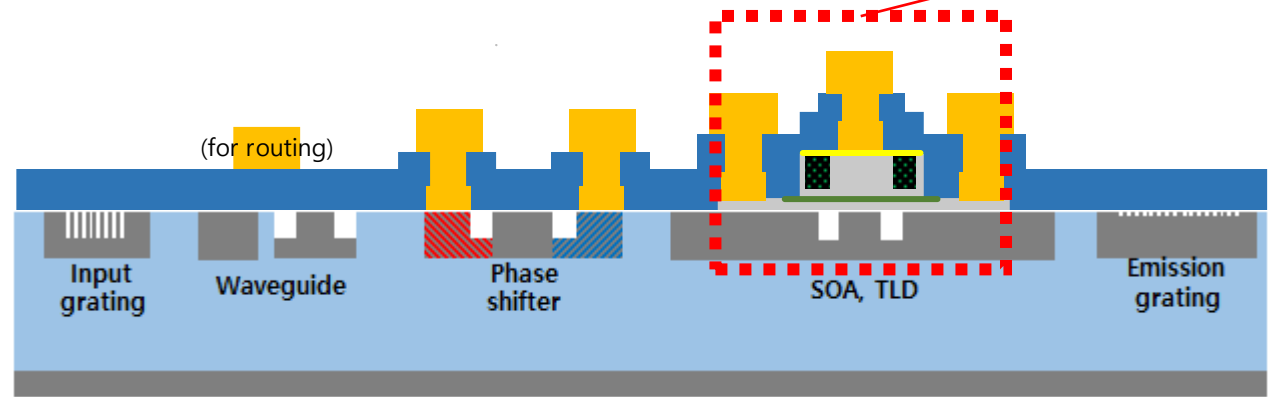
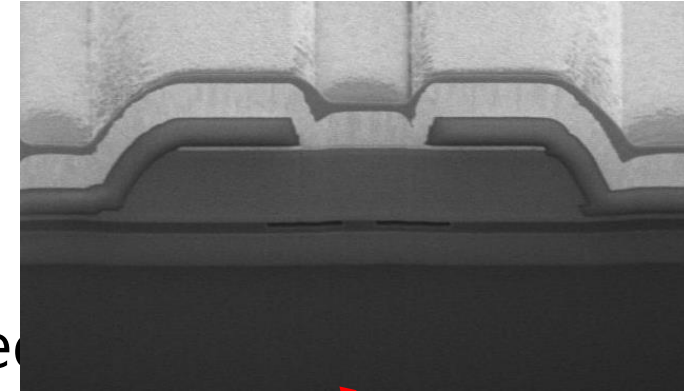
- Proton implant to control current path



# Our Results : Fabrication process



- Top metal (Au) defined



# Our Results : Beam Scanning

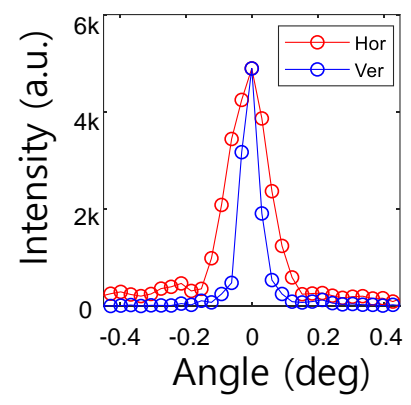
- 2D beam steering without moving parts
  - Phase control(Horizontal scan), Wavelength control(Vertical scan)



# Our Results : Beam Scanning

## 2D beam steering performance

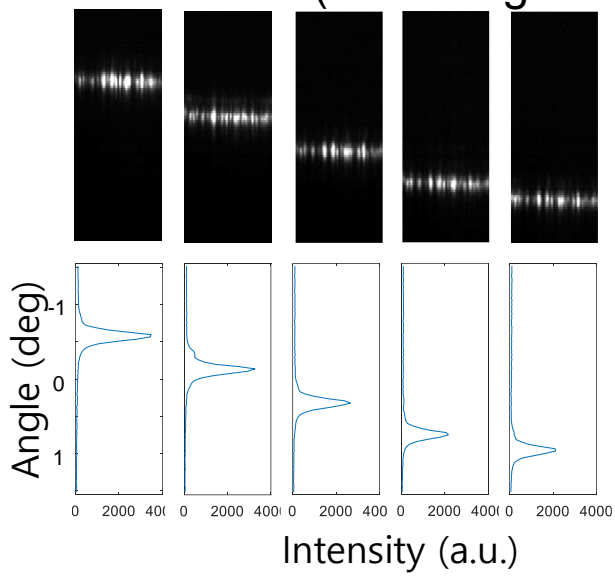
Genetic algorithm used for 32 channels  
 Beam size :  $0.15^\circ(\text{H}) \times 0.09^\circ(\text{V})$   
 FOV :  $20^\circ(\text{H}) \times 3.5^\circ(\text{V})$



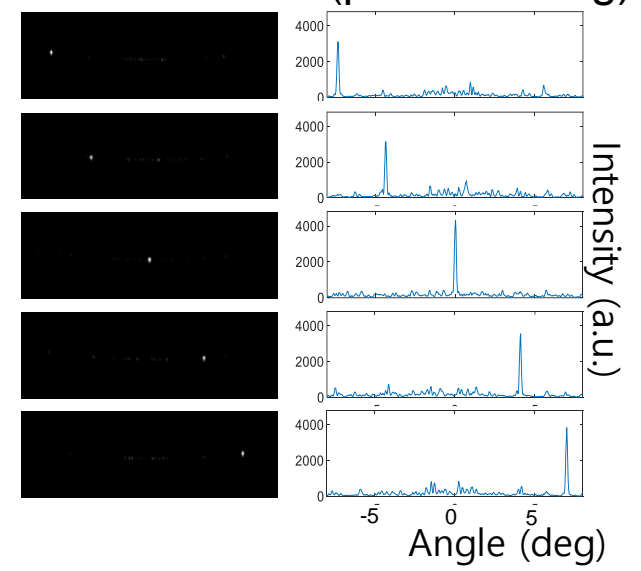
IEDM2020

### 2D beam scanning method (captured by IR Camera)

Vertical scan (wavelength tuning)

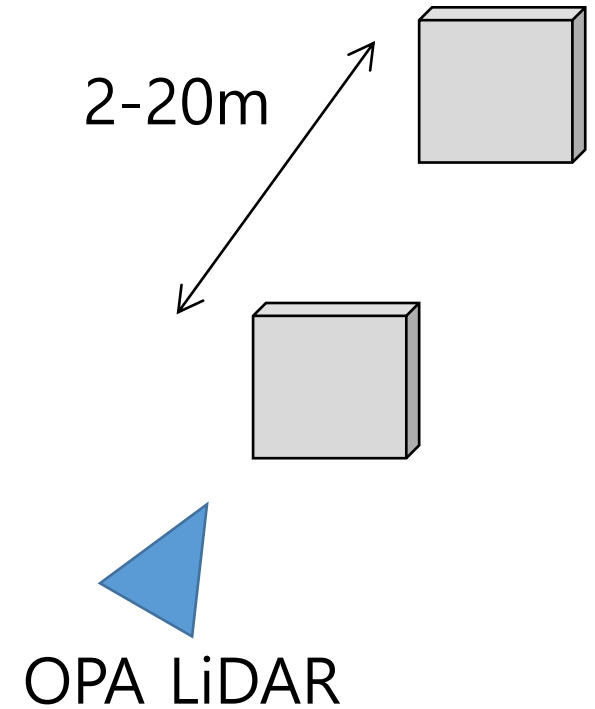
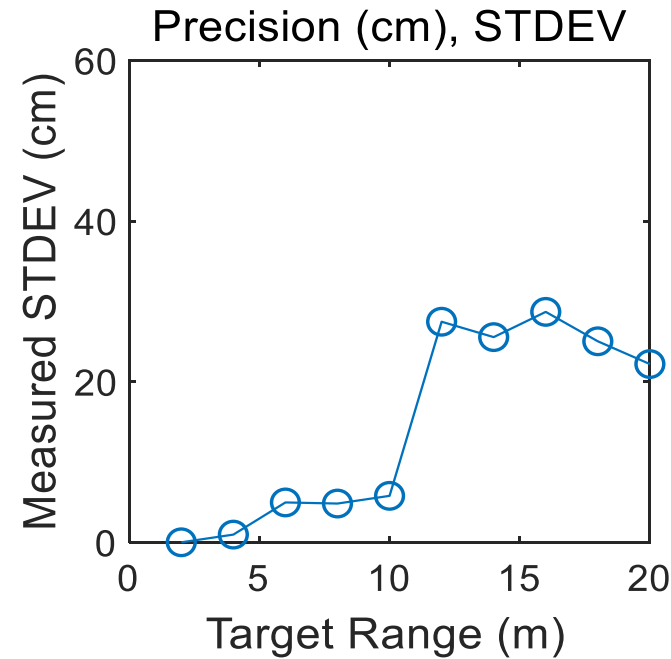
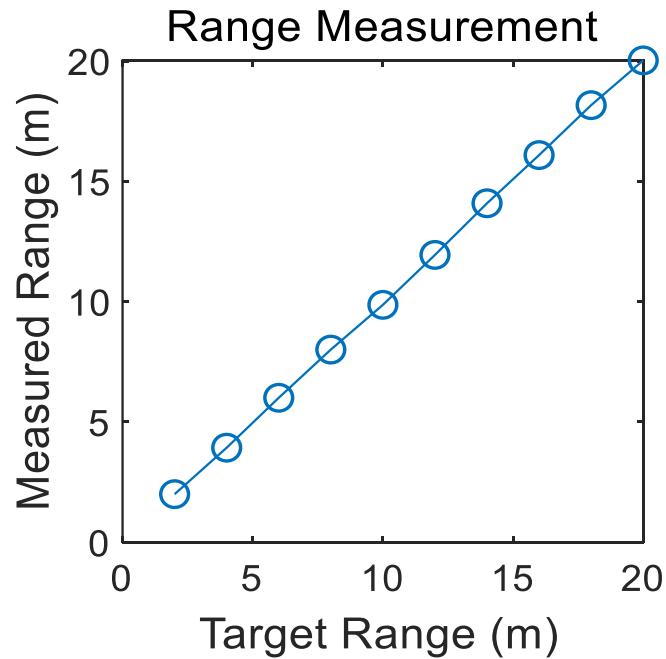


Horizontal scan (phase tuning)



# Our Results : Ranging

- Depth measurement up to 20m under 100,000lx
  - Accuracy 5.8cm
  - Precision 22cm (1%) at 20m distance



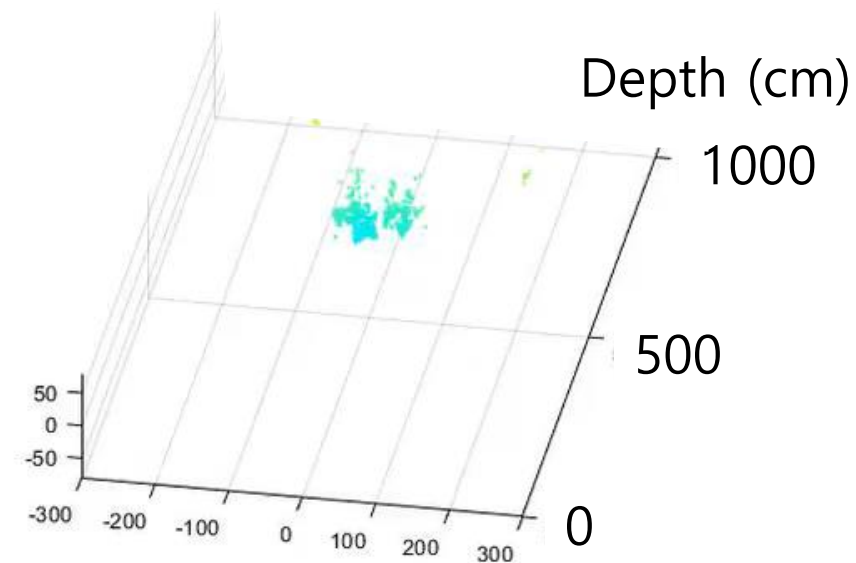
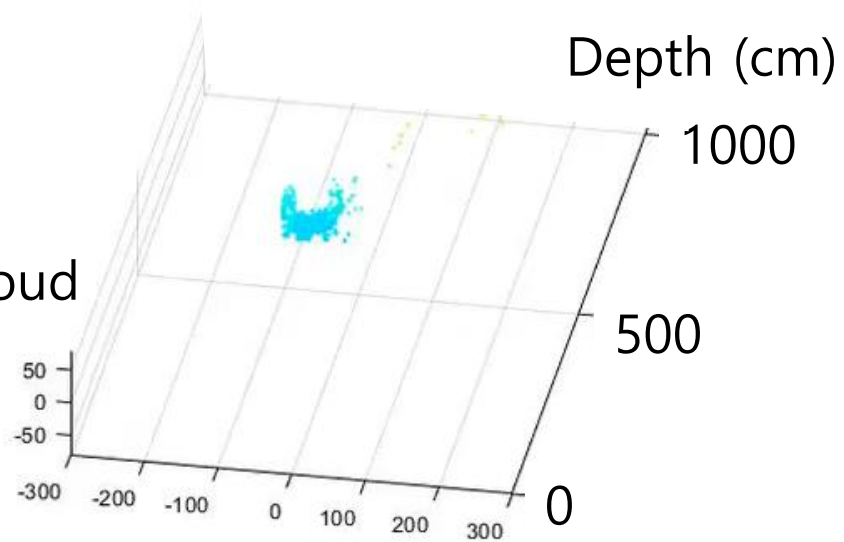
# Our Results : Demonstration

- Real time imaging with sunlight interference of 100,000lx
- Ranging up to 10m @ 20fps

Camera



3D Point Cloud





# Ongoing Field Test

- Test for LiDAR helping blind spots in ADAS level
- Measurement with Camera-based ADAS + Samsung LiDAR



# Summary

- We considered optimal LIDAR technologies in the wavelength, lighting, scanning and detection.
- We demonstrated 20m ranging and 10m real-time LiDAR operation with single-chip OPA.
- We are verifying our LiDAR can cover various issues in ADAS.